

INFORMATION DISCLOSURE CITATION  
(Use several sheets if necessary)

MAR 31 2004

ATTY DOCKET NO.  
2160-BA (FJ-99-36-1B)

SERIAL NO.  
10/625,576

Erland R. Sandstrom et al.

FILING  
July 23, 2003

GROUP  
1772

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	TRADEMARKS DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
9n.p.	U.S. Patent 3,183,552	5/18/65	Farkas	18	5	1/25/65
9n.p.	U.S. Patent 3,339,231	9/5/67	Piotrowski	18	5	10/1/67
9n.p.	U.S. Patent 3,819,314	6/25/74	Marcus	425	249	5/31/72
9n.p.	U.S. Patent 3,951,903	4/20/76	Shaffer	260	37 PC	11/1/74
9n.p.	U.S. Patent 4,046,836	9/6/77	Adelmann et al.	260	860	1/14/76
9n.p.	U.S. Patent 4,081,395	3/28/78	Talley	252	106	3/25/78
9n.p.	U.S. Patent 4,139,517	2/13/79	Zaganiacz	260	37 PC	4/12/77
9n.p.	U.S. Patent 4,193,494	3/18/80	Green	206	217	1/24/79
9n.p.	U.S. Patent 4,225,304	9/30/80	Valyi	425	526	11/25/77
9n.p.	U.S. Patent 4,230,298	10/28/80	Valyi	249	65	1/24/79
9n.p.	U.S. Patent 4,234,302	11/18/80	Valyi	425	526	1/24/79

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
9n.p.	Canadian Pat. 995,418 /	8/24/76	Canada	—	—	✓	
9n.p.	Offen. 2 007 552 /	9/2/71	Germany	81c	11	✓	
9n.p.	EPO Pub. 1 008 528 A2 /	6/14/00	EPO	B65D	1/46	✓	
9n.p.	EPO Pub. 0 167 660 A2 /	1/15/86	EPO	B29C	49/06	✓	
9n.p.	EPO Pub. 0 753 540 A2 /	1/15/97	EPO	C08L	69/00	✓	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

9n.p. DATA BASE WPI, Section Ch, Week 199719, Derwent Publications Ltd., London, GB; Class A23, AN 1997-209397, XP002176702 & JP 09 059367  
 Patent Abstracts of Japan, vol. 017, no. 576 (M-1499), 20 October 1993 & JP 05 169521 A (SEKISUI CHEM CO LTD), 9 July 1993  
 Patent Abstracts of Japan, vol. 1998, no. 06j, 30 April 1998 & JP 10 046021 A to NIPPON G II PLAST KK

9n.p. Kirk-Othmer Encyclopedia of Chemical Technology, Foruth Edition, Vol. 19, p. 600

EXAMINER

Mark Patterson

DATE CONSIDERED

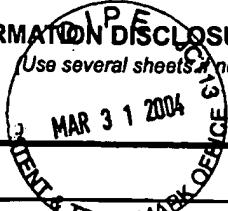
7/16/05

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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M.P.	U.S. Patent 4,308,086	12/29/81	Valyi	156	423	5/27/80
M.P.	U.S. Patent 4,513,037	4/23/85	Collins	428	35	12/29/83
M.P.	U.S. Patent 4,540,543	9/10/85	Thomas et al.	264	526	6/11/84
M.P.	U.S. Patent 5,145,895	9/8/92	Kohler et al.	524	160	7/29/91
M.P.	U.S. Patent 5,223,162	6/29/93	Rosso	252	33.2	12/6/91
M.P.	U.S. Patent 5,427,269	6/27/95	Willbrandt	220	669	6/14/94
M.P.	U.S. Patent 5,433,337	7/18/95	Willbrndt	220	669	1/28/94
M.P.	U.S. Patent 5,449,089	9/12/95	Turner et al.	220	675	2/2/94
M.P.	U.S. Patent 5,466,413	11/14/95	Richter et al.	264	521	8/26/93
M.P.	U.S. Patent 5,494,952	2/27/96	Hirata et al.	524	139	5/10/95
M.P.	U.S. Patent 5,693,278	12/2/97	Clements	264	176.1	12/14/97

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
M.P.	EPO Pub. 0 640 646 A1	3/1/95	EPO	C08K	5/42	✓	
M.P.	PCT Pub. WO 95/02979	2/2/95	PCT	A47G	19/23		✓
M.P.	Jap. Pub. 53 64262	6/8/78	Japan	C08L	69/00		✓
M.P.	EPO Pub. 0 511 617 A1	11/4/92	EPO	B29C	49/64	✓	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


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